## P-Channel Enhancement Mode MOSFET

## Features

## Pin Description

- $-30 \mathrm{~V} /-100 \mathrm{~A}$,
$\mathrm{R}_{\mathrm{DS}(\mathrm{ON})}=2.8 \mathrm{~m} \Omega$ (max.) $@ \mathrm{~V}_{\text {GS }}=-10 \mathrm{~V}$
$R_{\text {DS(ON) }}=4.3 \mathrm{~m} \Omega$ (max.) @ $\mathrm{V}_{\text {GS }}=-4.5 \mathrm{~V}$
- Reliable and Rugged
- Lead Free and Green Devices Available
(RoHS Compliant)
- HBM ESD Capability level of 6.6 KV typical

Note : The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

## Applications

- Power Management in Notebook Computer, Portable Equipment and Battery Powered Systems.


P-Channel MOSFET

## Ordering and Marking Information

| SM4311PS | Package Code <br> KP: DFN5x6A-8_EP <br> Operating Junction Temperature Range <br> C: -55 to $150{ }^{\circ} \mathrm{C}$ |
| :--- | :--- | :--- |
| Handling Code |  |
| TR : Tape \& Reel |  |
| Assembly Material |  |
| G: Halogen and Lead Free Device |  |

Note : SINOPOWER lead-free products contain molding compounds/die attach materials and 100\% matte tin plate termination finish; which are fully compliant with RoHS. SINOPOWER lead-free products meet or exceed the leadfree requirements of IPC/JEDEC J-STD-020D for MSL classification at lead-free peak reflow temperature. SINOPOWER defines "Green" to mean lead-free (RoHS compliant) and halogen free ( Br or Cl does not exceed 900 ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

SINOPOWER reserves the right to make changes to improve reliability or manufacturability without notice, and advise customers to obtain the latest version of relevant information to verify before placing orders.

Absolute Maximum Ratings $\left(T_{A}=25^{\circ} \mathrm{C}\right.$ Unless Otherwise Noted)

| Symbol | Parameter |  | Rating | Unit |
| :---: | :---: | :---: | :---: | :---: |
| Common Ratings ( $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ Unless Otherwise Noted) |  |  |  |  |
| $V_{\text {DSS }}$ | Drain-Source Voltage |  | -30 | V |
| $V_{\text {GSS }}$ | Gate-Source Voltage |  | $\pm 20$ |  |
| $\mathrm{T}_{J}$ | Maximum Junction Temperature |  | 150 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\text {STG }}$ | Storage Temperature Range |  | -55 to 150 |  |
| $\mathrm{I}_{\text {s }}$ | Diode Continuous Forward Current | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | $-100^{\text {a }}$ | A |
| $I_{\text {D }}$ | Continuous Drain Current | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | $-100^{\text {a }}$ |  |
|  |  | $\mathrm{T}_{\mathrm{C}}=100^{\circ} \mathrm{C}$ | $-100^{\text {a }}$ |  |
| $\mathrm{I}_{\mathrm{DM}}$ | Pulsed Drain Current | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | $-400{ }^{\text {b }}$ |  |
| $\mathrm{P}_{\mathrm{D}}$ | Maximum Power Dissipation | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | 125 | W |
|  |  | $\mathrm{T}_{\mathrm{C}}=100^{\circ} \mathrm{C}$ | 50 |  |
| $\mathrm{R}_{\text {өJC }}$ | Thermal Resistance-Junction to Case | Steady State | 1 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| $I_{\text {D }}$ | Continuous Drain Current | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | -41.8 | A |
|  |  | $\mathrm{T}_{\mathrm{A}}=70^{\circ} \mathrm{C}$ | -33.5 |  |
| $\mathrm{P}_{\mathrm{D}}$ | Maximum Power Dissipation | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | 7.4 | W |
|  |  | $\mathrm{T}_{\mathrm{A}}=70^{\circ} \mathrm{C}$ | 4.7 |  |
| $\mathrm{R}_{\theta \text { JA }}$ | Thermal Resistance-Junction to Ambient | $t \leq 10$ s | 17 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
|  |  | Steady State | 55 |  |
| $\mathrm{I}_{\text {As }}{ }^{\text {c }}$ | Avalanche Current, Single pulse ( $\mathrm{L}=0.5 \mathrm{mH}$ ) |  | 25 | A |
| $\mathrm{EAS}^{\text {c }}$ | Avalanche Energy, Single pulse ( $\mathrm{L}=0.5 \mathrm{mH}$ ) |  | 156.25 | mJ |

Note a : Package is limited to 100A.
Note b: Pulse width limited by max. junction temperature.
Note c: UIS tested and pulse width limited by maximum junction temperature $150^{\circ} \mathrm{C}$ (initial temperature $\mathrm{T}_{\mathrm{j}}=25^{\circ} \mathrm{C}$ ).

## Electrical Characteristics ( $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ Unless Otherwise Noted)

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Static Characteristics |  |  |  |  |  |  |
| BV DSS | Drain-Source Breakdown Voltage | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{I}_{\mathrm{DS}}=-250 \mu \mathrm{~A}$ | -30 | - | - | V |
| I DSs | Zero Gate Voltage Drain Current | $V_{\text {DS }}=-24 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}$ | - | - | -1 | $\mu \mathrm{A}$ |
|  |  | $\mathrm{T}_{\mathrm{J}}=85^{\circ} \mathrm{C}$ | - | - | -30 |  |
| $V_{G S(t h)}$ | Gate Threshold Voltage | $V_{\text {DS }}=V_{G S}, \mathrm{I}_{\text {DS }}=-250 \mu \mathrm{~A}$ | -1.3 | -1.8 | -2.3 | V |
| $\mathrm{I}_{\text {gss }}$ | Gate Leakage Current | $\mathrm{V}_{G S}= \pm 20 \mathrm{~V}, \mathrm{~V}_{\mathrm{DS}}=0 \mathrm{~V}$ | - | - | $\pm 100$ | nA |
| $\mathrm{R}_{\text {DS(ON) }}{ }^{\text {d }}$ | Drain-Source On-state Resistance | $V_{G S}=-10 \mathrm{~V}, \mathrm{I}_{\text {DS }}=-25 \mathrm{~A}$ | - | 2.2 | 2.8 | $\mathrm{m} \Omega$ |
|  |  | $\mathrm{V}_{\mathrm{GS}}=-4.5 \mathrm{~V}, \mathrm{I}_{\mathrm{DS}}=-20 \mathrm{~A}$ | - | 3.1 | 4.3 |  |

Electrical Characteristics (Cont.) ( $T_{A}=25^{\circ} \mathrm{C}$ Unless Otherwise Noted)

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Diode Characteristics |  |  |  |  |  |  |
| $V_{S D}{ }^{\text {d }}$ | Diode Forward Voltage | $\mathrm{I}_{S D}=-1 \mathrm{~A}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}$ | - | -0.7 | -1 | V |
| $\mathrm{trr}^{\text {e }}$ | Reverse Recovery Time | $\left\{\begin{array}{l} \mathrm{l}_{\mathrm{sD}}=-40 \mathrm{~A}, \\ \mathrm{di}_{\mathrm{sD}} / \mathrm{dt}=100 \mathrm{~A} / \mu \mathrm{s} \end{array}\right.$ | - | 46 | - | ns |
| $\mathrm{Q}_{\mathrm{rr}}{ }^{\text {e }}$ | Reverse Recovery Charge |  | - | 52 | - | nC |
| Dynamic Characteristics ${ }^{\text {e }}$ |  |  |  |  |  |  |
| $\mathrm{R}_{\mathrm{g}}$ | Gate Resistance | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{DS}}=0 \mathrm{~V}, \mathrm{~F}=1 \mathrm{MHz}$ | - | 1.8 | - | $\Omega$ |
| $\mathrm{C}_{\text {iss }}$ | Input Capacitance | $\begin{aligned} & V_{G S}=0 \mathrm{~V}, \\ & V_{D S}=-15 \mathrm{~V}, \\ & \text { Frequency }=1.0 \mathrm{MHz} \end{aligned}$ | - | 8900 | - | pF |
| $\mathrm{C}_{\text {oss }}$ | Output Capacitance |  | - | 1560 | - |  |
| $\mathrm{C}_{\text {rss }}$ | Reverse Transfer Capacitance |  | - | 1160 | - |  |
| $\mathrm{t}_{\mathrm{d}(\mathrm{ON})}$ | Turn-on Delay Time | $\begin{aligned} & V_{D D}=-15 \mathrm{~V}, R_{L}=15 \Omega, \\ & I_{D S}=-1 A, V_{G E N}=-10 \mathrm{~V}, \\ & R_{G}=6 \Omega \end{aligned}$ | - | 28 | - | ns |
| $\mathrm{t}_{\mathrm{r}}$ | Turn-on Rise Time |  | - | 26 | - |  |
| $\mathrm{t}_{\text {d(OFF) }}$ | Turn-off Delay Time |  | - | 260 | - |  |
| $\mathrm{t}_{\mathrm{f}}$ | Turn-off Fall Time |  | - | 135 | - |  |
| Gate Charge Characteristics ${ }^{\text {e }}$ |  |  |  |  |  |  |
| $Q_{g}$ | Total Gate Charge | $\begin{aligned} & V_{D S}=-15 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=-10 \mathrm{~V}, \\ & \mathrm{l}_{\mathrm{DS}}=-40 \mathrm{~A} \end{aligned}$ | - | 186 | - | $n C$ |
| $\mathrm{Q}_{\mathrm{gs}}$ | Gate-Source Charge |  | - | 22 | - |  |
| $\mathrm{Q}_{\mathrm{gd}}$ | Gate-Drain Charge |  | - | 42 | - |  |

Note d: Pulse test ; pulse width $\leq 300 \mu \mathrm{~s}$, duty cycle $\leq 2 \%$.
Note e : Guaranteed by design, not subject to production testing.

## Typical Operating Characteristics



## Typical Operating Characteristics (Cont.)

Output Characteristics


Gate-Source On Resistance


Drain-Source On Resistance


Gate Threshold Voltage

$\mathrm{T}_{\mathrm{j}}$ - Junction Temperature $\left({ }^{\circ} \mathrm{C}\right)$

## Typical Operating Characteristics (Cont.)

Drain-Source On Resistance


Capacitance

$-\mathrm{V}_{\mathrm{DS}}$ - Drain - Source Voltage (V)

## Source-Drain Diode Forward



Gate Charge

$\mathrm{Q}_{\mathrm{G}}$ - Gate Charge (nC)

## Avalanche Test Circuit and Waveforms



## Switching Time Test Circuit and Waveforms



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## Classification Profile



## Classification Reflow Profiles

| Profile Feature | Sn-Pb Eutectic Assembly | Pb-Free Assembly |
| :---: | :---: | :---: |
| Preheat \& Soak <br> Temperature $\min \left(\mathrm{T}_{\text {smin }}\right)$ <br> Temperature max ( $\mathrm{T}_{\text {smax }}$ ) <br> Time ( $\mathrm{T}_{\text {smin }}$ to $\mathrm{T}_{\text {smax }}$ ) ( $\mathrm{t}_{\mathrm{s}}$ ) | $\begin{gathered} 100^{\circ} \mathrm{C} \\ 150^{\circ} \mathrm{C} \\ 60-120 \text { seconds } \end{gathered}$ | $\begin{gathered} 150^{\circ} \mathrm{C} \\ 200^{\circ} \mathrm{C} \\ 60-120 \text { seconds } \end{gathered}$ |
| Average ramp-up rate ( $\mathrm{T}_{\text {smax }}$ to $\mathrm{T}_{\mathrm{P}}$ ) | $3^{\circ} \mathrm{C} /$ second max. | $3^{\circ} \mathrm{C} /$ second max. |
| Liquidous temperature ( $\mathrm{T}_{\mathrm{L}}$ ) <br> Time at liquidous ( $\mathrm{t}_{\mathrm{L}}$ ) | $\begin{gathered} 183^{\circ} \mathrm{C} \\ 60-150 \text { seconds } \end{gathered}$ | $\begin{gathered} 217{ }^{\circ} \mathrm{C} \\ 60-150 \text { seconds } \end{gathered}$ |
| Peak package body Temperature $\left(T_{p}\right)^{*}$ $\left(T_{\mathrm{p}}\right)^{*}$ | See Classification Temp in table 1 | See Classification Temp in table 2 |
| Time ( $\left.\mathrm{t}_{\mathrm{p}}\right)^{* *}$ within $5^{\circ} \mathrm{C}$ of the specified classification temperature ( $T_{c}$ ) | 20** seconds | 30** seconds |
| Average ramp-down rate ( $\mathrm{T}_{\mathrm{p}}$ to $\mathrm{T}_{\text {smax }}$ ) | $6^{\circ} \mathrm{C} /$ second max. | $6^{\circ} \mathrm{C} /$ second max. |
| Time $25^{\circ} \mathrm{C}$ to peak temperature | 6 minutes max. | 8 minutes max. |

Table 1. SnPb Eutectic Process - Classification Temperatures (Tc)

| Package <br> Thickness | Volume mm <br> 3 <br> $<350$ | Volume mm $^{3}$ |
| :---: | :---: | :---: |
| $<2.5 \mathrm{~mm}$ | $235^{\circ} \mathrm{C}$ | $220^{\circ} \mathrm{C}$ |
| $\geq 2.5 \mathrm{~mm}$ | $220^{\circ} \mathrm{C}$ | $220^{\circ} \mathrm{C}$ |

Table 2. Pb-free Process - Classification Temperatures (Tc)

| Package Thickness | $\begin{gathered} \text { Volume } \mathrm{mm}^{3} \\ <350 \end{gathered}$ | $\begin{gathered} \text { Volume } \mathrm{mm}^{3} \\ 350-2000 \end{gathered}$ | $\begin{gathered} \text { Volume } \mathrm{mm}^{3} \\ >2000 \end{gathered}$ |
| :---: | :---: | :---: | :---: |
| $<1.6 \mathrm{~mm}$ | $260{ }^{\circ} \mathrm{C}$ | $260{ }^{\circ} \mathrm{C}$ | $260{ }^{\circ} \mathrm{C}$ |
| $1.6 \mathrm{~mm}-2.5 \mathrm{~mm}$ | $260{ }^{\circ} \mathrm{C}$ | $250{ }^{\circ} \mathrm{C}$ | $245{ }^{\circ} \mathrm{C}$ |
| $\geq 2.5 \mathrm{~mm}$ | $250{ }^{\circ} \mathrm{C}$ | $245{ }^{\circ} \mathrm{C}$ | $245{ }^{\circ} \mathrm{C}$ |

## Reliability Test Program

| Test item | Method | Description |
| :--- | :--- | :--- |
| SOLDERABILITY | JESD-22, B102 | $5 \mathrm{Sec}, 245^{\circ} \mathrm{C}$ |
| HTRB | JESD-22, A108 | $1000 \mathrm{Hrs}, 80 \%$ of VDS max @ Tjmax |
| HTGB | JESD-22, A108 | $1000 \mathrm{Hrs}, 100 \%$ of VGS max @ Tjmax |
| PCT | JESD-22, A102 | $168 \mathrm{Hrs}, 100 \%$ RH, $2 \mathrm{~atm}, 121^{\circ} \mathrm{C}$ |
| TCT | JESD-22, A104 | $500 \mathrm{Cycles},-65^{\circ} \mathrm{C} \sim 150^{\circ} \mathrm{C}$ |

## Customer Service

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